

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/815,239	AHUJA ET AL.	
		Examiner	Art Unit	Page 1 of 1
		Shin-Hon Chen	2131	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0129140	09-2002	Peled et al.	709/224
*	B	US-2003/0084300	05-2003	Koike, Yuichi	713/182
*	C	US-7,093,288	08-2006	Hydrie et al.	726/13
*	D	US-2004/0001498	01-2004	Chen et al.	370/401
*	E	US-2003/0084326	05-2003	Tarquini, Richard Paul	713/200
*	F	US-2003/0028493	02-2003	Tajima et al.	705/67
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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